Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/805,158	ONO ET AL.
Examiner	Art Unit

2814

Marcos D. Pizarro-Crespo

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SEARCHED					
Class	Subclass	Date	Examiner		
257	288,295 310,314 324-326 410,411	7/14/2005	MDP		
					
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INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
EAST search for paper no. 0705 made of record.	7/14/2005	MDP		
IEEE Xplore search for paper no. 0705 made of record.	7/14/2005	MDP		
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